

CMOS Digital Integrated Circuits Silicon Monolithic

TC7SZ125F

1. Functional Description

Bus Buffer with 3-State Output

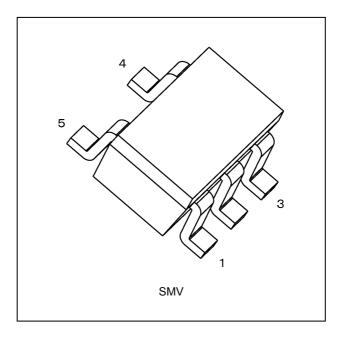
2. Features

- (1) AEC-Q100 (Rev. H) (Note 1)
- (2) Wide operating temperature range: $T_{opr} = -40$ to 125 °C (Note 2)
- (3) High output current: ± 24 mA (min) at $V_{CC} = 3.0$ V
- (4) Super high speed operation: $t_{pd} = 2.6$ ns (typ.) at $V_{CC} = 5.0$ V, $C_L = 50$ pF
- (5) Operation voltage range: $V_{CC} = 1.65$ to 5.5 V
- (6) 5.5 V tolerant inputs
- (7) 5.5 V power down protection output
- (8) Matches the performance of TC74LCX series when operated at 3.3 V $V_{\rm CC}$

Note 1: This device is compliant with the reliability requirements of AEC-Q100. For details, contact your Toshiba sales representative.

Note 2: For devices with the ordering part number ending in J(CT. T_{opr} = -40 to 85 °C for the other devices.

3. Packaging

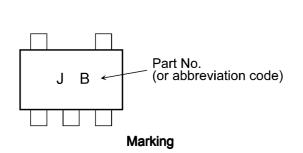


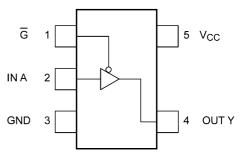
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Start of commercial production



4. Marking and Pin Assignment





Pin Assignment (Top view)

5. IEC Logic Symbol



6. Truth Table

Input A	Input G	Output Y
Х	Н	Z
L	L	L
Н	L	Н

X: Don't care

Z: High impedance

7. Absolute Maximum Ratings (Note) (Unless otherwise specified, T_a = 25 °C)

Characteristics	Symbol	Note	Rating	Unit
Supply voltage	V _{CC}		-0.5 to 6.0	V
Input voltage	V _{IN}		-0.5 to 6.0	V
DC output voltage	V _{OUT}	(Note 1)	-0.5 to 6.0	V
		(Note 2)	-0.5 to V _{CC} + 0.5	
Input diode current	I _{IK}		-20	mA
Output diode current	l _{ok}	(Note 3)	-20	mA
DC output current	I _{OUT}		±50	mA
V _{CC} /ground current	I _{CC}		±50	mA
Power dissipation	P _D		200	mW
Storage temperature	T _{stg}		-65 to 150	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: V_{CC} = 0 V or high impedance condition

Note 2: High (H) or Low (L) state. I_{OUT} absolute maximum rating must be observed.

Note 3: V_{OUT} < GND



8. Operating Ranges (Note)

Characteristics	Symbol	Note	Test Condition	Rating	Unit
Supply voltage	V _{CC}		_	1.65 to 5.5	V
		(Note 1)	_	1.5 to 5.5	
Input voltage	V_{IN}		_	0 to 5.5	V
Output voltage	V _{OUT}	(Note 2)	_	0 to 5.5	V
		(Note 3)	_	0 to V _{CC}	
Operating temperature	T_{opr}	(Note 4)	_	-40 to 125	°C
		(Note 5)	_	-40 to 85	
Input rise and fall time	dt/dv		V_{CC} = 1.8 \pm 0.15 V, 2.5 \pm 0.2 V	0 to 20	ns/V
			$V_{CC} = 3.3 \pm 0.3 \text{ V}$	0 to 10	
			$V_{CC} = 5.0 \pm 0.5 \text{ V}$	0 to 5	

Note: The operating ranges must be maintained to ensure the normal operation of the device.

Unused inputs must be tied to either V_{CC} or GND.

Note 1: Data retention only

Note 2: V_{CC} = 0 V or high impedance condition

Note 3: High (H) or Low (L) state.

Note 4: For devices with the ordering part number ending in J(CT.

Note 5: For devices except those with the ordering part number ending in J(CT.

9. Electrical Characteristics

9.1. DC Characteristics (Unless otherwise specified, T_a = 25 °C)

Characteristics	Symbol	Test Condition		V _{CC} (V)	Min	Тур.	Max	Unit
High-level input voltage	V _{IH}	_		1.65 to 1.95	V _{CC} × 0.88	_	_	V
				2.3 to 5.5	V _{CC} × 0.75	_	_	
Low-level input voltage	V _{IL}	_		1.65 to 1.95	_	_	V _{CC} × 0.12	V
				2.3 to 5.5	_	_	V _{CC} × 0.25	
High-level output voltage	V _{OH}	V _{IN} = V _{IH} or V _{IL}	I _{OH} = -100 μA	1.65	1.55	1.65	_	V
				2.3	2.2	2.3	_	
				3.0	2.9	3.0	_	
				4.5	4.4	4.5	_	
			I _{OH} = -8 mA	2.3	1.9	2.15	_	
			I _{OH} = -16 mA	3.0	2.4	2.8	_	
			I _{OH} = -24 mA	3.0	2.3	2.68	_	
			I _{OH} = -32 mA	4.5	3.8	4.2	_	
Low-level output voltage	V _{OL}	V _{IN} = V _{IL}	I _{OL} = 100 μA	1.65	_	0.0	0.1	V
				2.3	_	0.0	0.1	
				3.0	_	0.0	0.1	
				4.5	_	0.0	0.1	
			I _{OL} = 8 mA	2.3	_	0.1	0.3	
			I _{OL} = 16 mA	3.0	_	0.15	0.4	
			I _{OL} = 24 mA	3.0	_	0.22	0.55	
			I _{OL} = 32 mA	4.5	_	0.22	0.55	
Input leakage current	I _{IN}	V _{IN} = 5.5 V or GND		0 to 5.5	_	_	±1.0	μΑ
3-state output OFF-state leakage current	I _{OZ}	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = 0 \text{ to } 5.5 \text{ V}$		1.65 to 5.5	_	_	±1.0	μА
Power-OFF leakage current	I _{OFF}	V _{IN} or V _{OUT} = 5.5 V		0	_	_	1	μА
Quiescent supply current	I _{CC}	V _{IN} = V _{CC} or GND		5.5	_	_	2	μА



9.2. DC Characteristics (Unless otherwise specified, T_a = -40 to 85 °C)

Characteristics	Symbol	Test Conditio	n	V _{CC} (V)	Min	Max	Unit
High-level input voltage	V _{IH}	_		1.65 to 1.95	V _{CC} × 0.88	_	V
				2.3 to 5.5	$V_{CC} \times 0.75$	_	
Low-level input voltage	V _{IL}	_		1.65 to 1.95	_	V _{CC} × 0.12	٧
				2.3 to 5.5	-	$V_{CC} \times 0.25$	
High-level output voltage	V _{OH}	$V_{IN} = V_{IH}$ or V_{IL}	I _{OH} = -100 μA	1.65	1.55	_	V
				2.3	2.2	_	
				3.0	2.9	_	
				4.5	4.4	_	
			I _{OH} = -8 mA	2.3	1.9	_	
			I _{OH} = -16 mA	3.0	2.4	_	
			I _{OH} = -24 mA	3.0	2.3	_	
			I _{OH} = -32 mA	4.5	3.8	_	
Low-level output voltage	V _{OL}	$V_{IN} = V_{IL}$	I _{OL} = 100 μA	1.65	_	0.1	V
				2.3	_	0.1	
				3.0	_	0.1	
				4.5	_	0.1	
			I _{OL} = 8 mA	2.3	_	0.3	
			I _{OL} = 16 mA	3.0	_	0.4	
			I _{OL} = 24 mA	3.0	_	0.55	
			I _{OL} = 32 mA	4.5	_	0.55	
Input leakage current	I _{IN}	V _{IN} = 5.5 V or GND		0 to 5.5	_	±10.0	μΑ
3-state output OFF-state leakage current	I _{OZ}	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = 0 \text{ to } 5.5 \text{ V}$		1.65 to 5.5	_	±10.0	μА
Power-OFF leakage current	I _{OFF}	V _{IN} or V _{OUT} = 5.5 V		0		10	μΑ
Quiescent supply current	Icc	$V_{IN} = V_{CC}$ or GND		5.5	_	20	μΑ



9.3. DC Characteristics (Note) (Unless otherwise specified, T_a = -40 to 125 °C)

Characteristics	Symbol	Test Condition	า	V _{CC} (V)	Min	Max	Unit
High-level input voltage	V _{IH}	_		1.65 to 1.95	V _{CC} × 0.88	_	٧
				2.3 to 5.5	V _{CC} × 0.75	_	
Low-level input voltage	V _{IL}	_		1.65 to 1.95		V _{CC} × 0.12	٧
				2.3 to 5.5		$V_{CC} \times 0.25$	
High-level output voltage	V _{OH}	$V_{IN} = V_{IH}$ or V_{IL}	I _{OH} = -100 μA	1.65	1.55	_	V
				2.3	2.2	_	
				3.0	2.9	_	
				4.5	4.4	_	
			I_{OH} = -8 mA	2.3	1.7	_	
			I _{OH} = -16 mA	3.0	2.2	_	
			I _{OH} = -24 mA	3.0	2.0	_	
			I _{OH} = -32 mA	4.5	3.4	_	
Low-level output voltage	V _{OL}	V _{IN} = V _{IL}	I _{OL} = 100 μA	1.65	_	0.1	V
				2.3	_	0.1	
				3.0	_	0.1	
				4.5	_	0.1	
			I _{OL} = 8 mA	2.3	_	0.45	
			I _{OL} = 16 mA	3.0	_	0.6	
			I _{OL} = 24 mA	3.0	_	0.8	
			I _{OL} = 32 mA	4.5	_	0.8	
Input leakage current	I _{IN}	V _{IN} = 5.5 V or GND		0 to 5.5	_	±20.0	μΑ
3-state output OFF-state leakage current	I _{OZ}	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = 0 \text{ to } 5.5 \text{ V}$		1.65 to 5.5	_	±20.0	μА
Power-OFF leakage current	I _{OFF}	V _{IN} or V _{OUT} = 5.5 V		0		100	μА
Quiescent supply current	Icc	$V_{IN} = V_{CC}$ or GND		5.5	_	200	μΑ

Note: For devices with the ordering part number ending in J(CT.



9.4. AC Characteristics (Unless otherwise specified, $T_a = 25$ °C, Input: $t_f = t_f = 3$ ns)

Characteristics	Symbol	Note	Test Condition	V _{CC} (V)	C _L (pF)	Min	Тур.	Max	Unit
Propagation delay time	t _{PLH} ,t _{PHL}		$R_L = 1 M\Omega$	1.8 ± 0.15	15	2.0	5.3	11.0	ns
			See 9.7 AC Test Circuit, Table 9.7.1	2.5 ± 0.2		8.0	3.4	7.5	
			Circuit, Table 9.7.1	3.3 ± 0.3		0.5	2.5	5.2	
				5.0 ± 0.5		0.5	2.1	4.5	
			R_L = 500 $Ω$ See 9.7 AC Test	3.3 ± 0.3	50	1.5	3.2	5.7	ns
			Circuit, Table 9.7.1	5.0 ± 0.5		8.0	2.6	5.0	
Output enable time	t_{PZL}, t_{PZH}		R _L = 500 Ω	1.8 ± 0.15	50	2.0	7.0	12.5	ns
			See 9.7 AC Test Circuit, Table 9.7.1	2.5 ± 0.2		1.5	4.6	8.5	
			Circuit, Table 9.7.1	3.3 ± 0.3		1.5	3.5	6.2	
				5.0 ± 0.5		8.0	2.8	5.5	
Output disable time	t_{PLZ}, t_{PHZ}		R _L = 500 Ω	1.8 ± 0.15	50	2.0	5.4	11.0	ns
			See 9.7 AC Test Circuit, Table 9.7.1	2.5 ± 0.2		1.5	3.5	8.0	
			Circuit, Table 9.7.1	3.3 ± 0.3		1.0	2.8	5.7	
				5.0 ± 0.5		0.5	2.1	4.7	
Input capacitance	C _{IN}		_	0 to 5.5	_	_	4	_	pF
Power dissipation	C _{PD}	(Note 1)	_	3.3	_	_	17	_	pF
capacitance				5.5			24		

Note 1: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation. $I_{CC(opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$

9.5. AC Characteristics (Unless otherwise specified, $T_a = -40$ to 85 °C, Input: $t_r = t_f = 3$ ns)

Characteristics	Symbol	Test Condition	V _{CC} (V)	C _L (pF)	Min	Max	Unit	
Propagation delay time	t_{PLH}, t_{PHL}	$R_L = 1 M\Omega$	1.8 ± 0.15	15	2.0	11.5	ns	
		See 9.7 AC Test Circuit, Table 9.7.1	2.5 ± 0.2		8.0	8.0		
		Table 9.7.1	3.3 ± 0.3		0.5	5.5		
			5.0 ± 0.5		0.5	4.8		
		$R_L = 500 \Omega$	3.3 ± 0.3	50	1.5	6.0	ns	
		See 9.7 AC Test Circuit, Table 9.7.1	5.0 ± 0.5		0.8	5.3		
Output enable time	t_{PZL}, t_{PZH}	See 9.7 AC Test Circuit,	1.8 ± 0.15	50	2.0	13.0	ns	
			l ' l	See 9.7 AC Test Circuit, Table 9.7.1	2.5 ± 0.2		1.5	9.0
		Table 9.7.1	3.3 ± 0.3		1.5	6.5		
			5.0 ± 0.5		0.8	5.8		
Output disable time	t_{PLZ}, t_{PHZ}	R _L = 500 Ω	1.8 ± 0.15	50	2.0	12.0	ns	
	1	See 9.7 AC Test Circuit, Table 9.7.1	2.5 ± 0.2		1.5	8.5		
		Table 5.7.1	3.3 ± 0.3		1.0	6.0		
			5.0 ± 0.5		0.5	5.0		



9.6. AC Characteristics (Note) (Unless otherwise specified, T_a = -40 to 125 °C, Input: t_r = t_f = 3 ns)

Characteristics	Symbol	Test Condition	V _{CC} (V)	C _L (pF)	Min	Max	Unit	
Propagation delay time	t _{PLH} ,t _{PHL}	$R_L = 1 M\Omega$	1.8 ± 0.15	15	2.0	13.0	ns	
		See 9.7 AC Test Circuit, Table 9.7.1	2.5 ± 0.2		0.8	9.0		
		Table 9.7.1	3.3 ± 0.3		0.5	6.5		
			5.0 ± 0.5		0.5	5.5		
		$R_L = 500 \Omega$	3.3 ± 0.3	50	1.5	7.0	ns	
		See 9.7 AC Test Circuit, Table 9.7.1	5.0 ± 0.5		0.8	6.0		
Output enable time	t_{PZL}, t_{PZH}	t_{PZL}, t_{PZH} R _L = 500 Ω See 9.7 AC Test Circuit, Table 9.7.1	1.8 ± 0.15	50	2.0	14.5	ns	
			1 1	2.5 ± 0.2		1.5	10.0	
	Tuble 5.7.1			3.3 ± 0.3		1.5	7.5	
			5.0 ± 0.5		0.8	6.5		
Output disable time	t_{PLZ}, t_{PHZ}	R _L = 500 Ω	1.8 ± 0.15	50	2.0	13.5	ns	
		See 9.7 AC Test Circuit, Table 9.7.1	2.5 ± 0.2		1.5	9.5		
		Table 9.7.1	3.3 ± 0.3		1.0	7.0		
			5.0 ± 0.5		0.5	5.5		

Note: For devices with the ordering part number ending in J(CT.

9.7. AC Test Circuit

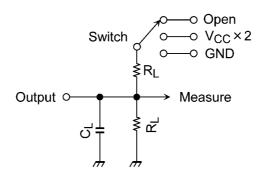


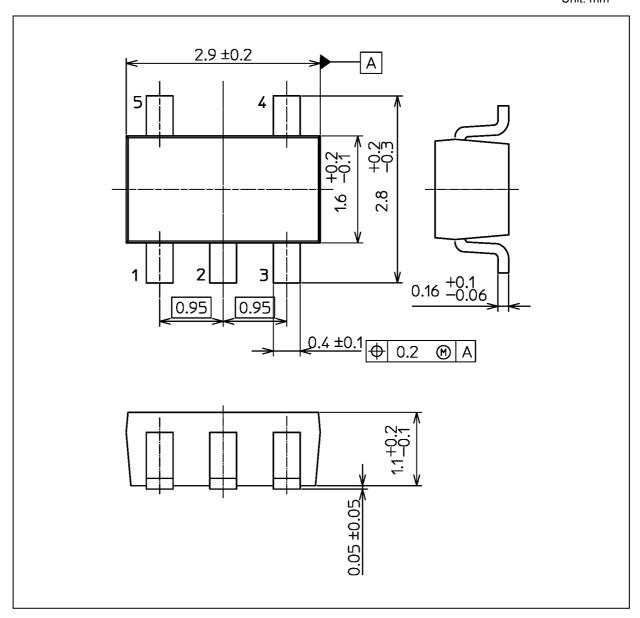
Table 9.7.1 Parameter for AC Test Circuit

Characteristics	Switch
t _{PLH} , t _{PHL}	Open
t _{PLZ} , t _{PZL}	V _{CC} × 2
t _{PHZ} , t _{PZH}	GND



Package Dimensions

Unit: mm



Weight: 14 mg (typ.)

	Package Name(s)
JEDEC: SOT-25	
Nickname: SMV	

Rev.3.0



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